



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Application of	: Hadamovsky, S., et al	Docket No.:	1/1200-1-C1
Serial No.	: 10/716,125	) Art Unit:	1641
Filed	: November 18, 2003	) Examiner:	Cheu, Changhwah J.
For	: Process for Label-free Measurement of Modified Substrate		

**Mail Stop Non-Fee Amendment  
Commissioner for Patents  
PO Box 1450  
Alexandria, VA 22313-1450**

**Preliminary Amendment**

Sir:

Prior to examination of the above-identified patent application please enter the following remarks :

**Remarks/Arguments** begin on page 2 of this paper.